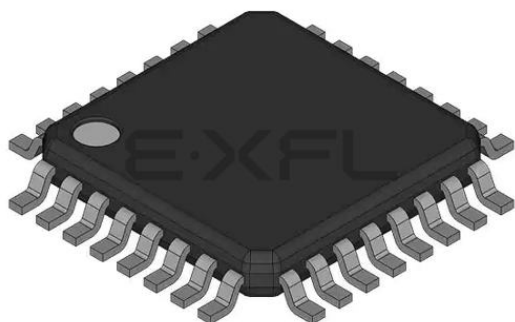




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Applications of "[Embedded - Microcontrollers](#)"

Details

Product Status	Active
Core Processor	Coldfire V1
Core Size	32-Bit Single-Core
Speed	50MHz
Connectivity	I ² C, SPI, UART/USART, USB OTG
Peripherals	DMA, I ² S, LVD, POR, PWM, WDT
Number of I/O	22
Program Memory Size	32KB (32K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	8K x 8
Voltage - Supply (Vcc/Vdd)	1.71V ~ 3.6V
Data Converters	A/D 6x12b; D/A 1x12b
Oscillator Type	External
Operating Temperature	-40°C ~ 105°C (TA)
Mounting Type	Surface Mount, Wettable Flank
Package / Case	32-VFQFN Exposed Pad
Supplier Device Package	32-HVQFN (5x5)
Purchase URL	https://www.e-xfl.com/pro/item?MUrl=&PartUrl=mcf51jf32vfm

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3.2.1 Example

This is an example of an operating behavior:

Symbol	Description	Min.	Max.	Unit
I_{WP}	Digital I/O weak pullup/pulldown current	10	130	μA

3.3 Definition: Attribute

An *attribute* is a specified value or range of values for a technical characteristic that are guaranteed, regardless of whether you meet the operating requirements.

3.3.1 Example

This is an example of an attribute:

Symbol	Description	Min.	Max.	Unit
CIN_D	Input capacitance: digital pins	—	7	pF

3.4 Definition: Rating

A *rating* is a minimum or maximum value of a technical characteristic that, if exceeded, may cause permanent chip failure:

- *Operating ratings* apply during operation of the chip.
- *Handling ratings* apply when the chip is not powered.

3.4.1 Example

This is an example of an operating rating:

Symbol	Description	Min.	Max.	Unit
V_{DD}	1.0 V core supply voltage	−0.3	1.2	V

Table 3. Voltage and current operating behaviors (continued)

Symbol	Description	Min.	Max.	Unit	Notes
I_{OZ}	Hi-Z (off-state) leakage current (per pin)	—	1	μA	
I_{OZ}	Total Hi-Z (off-state) leakage current (all input pins)	—	4	μA	
R_{PU}	Internal pullup resistors	22	50	$k\Omega$	2
R_{PD}	Internal pulldown resistors	22	50	$k\Omega$	3

1. Tested by ganged leakage method
2. Measured at $V_{input} = V_{SS}$
3. Measured at $V_{input} = V_{DD}$

5.2.4 Power mode transition operating behaviors

All specifications except t_{POR} and VLLSx-RUN recovery times in the following table assume this clock configuration:

- CPU and system clocks = 50 MHz
- Bus clock (and flash and Mini-FlexBus clocks) = 25 MHz

Table 4. Power mode transition operating behaviors

Symbol	Description	Min.	Max.	Unit	Notes
t_{POR}	After a POR event, amount of time from the point V_{DD} reaches 1.71 V to execution of the first instruction across the operating temperature range of the chip. • $1.71 V / (V_{DD} \text{ slew rate}) \leq 300 \mu s$ • $1.71 V / (V_{DD} \text{ slew rate}) > 300 \mu s$	—	$300 \cdot 1.71 V / (V_{DD} \text{ slew rate})$	μs	1
	• VLLS1 → RUN	—	132	μs	1, 2
	• VLLS2 → RUN	—	92	μs	1, 2
	• VLLS3 → RUN	—	92	μs	1, 2
	• LLS → RUN	—	7.5	μs	2
	• VLPS → RUN	—	5.5	μs	2
	• STOP → RUN	—	5.5	μs	2

1. Normal boot (FTFL_FOFT[LPBOOT] is 1)
2. The wakeup time includes the execution time for a small amount of firmware used to produce a GPIO clear event. Wakeup time is measured from the falling edge of the external wakeup event to the falling edge of a GPIO clear performed by software.

5.2.5 Power consumption operating behaviors

Table 5. Power consumption operating behaviors

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
I _{DDA}	Analog supply current	—	—	See note	mA	1
I _{DD_RUN}	Run mode current — all peripheral clocks disabled, code executing from RAM	—	13	—	mA	2
		—	13	16	mA	
		—	—	—	—	
I _{DD_RUN}	Run mode current — all peripheral clocks disabled, code executing from flash memory with page buffering disabled	—	14.3	—	mA	2
		—	14.5	17.9	mA	
		—	—	—	—	
I _{DD_RUN}	Run mode current — all peripheral clocks enabled, code executing from RAM, exercising flash memory	—	20	23.5	mA	3
		—	20	25	mA	
		—	—	—	—	
I _{DD_WAIT}	Wait mode current at 3.0 V — all peripheral clocks disabled	—	5.8	6.8	mA	4
I _{DD_STOP}	Stop mode current at 3.0 V	—	0.34	0.41	mA	
		—	0.90	1.8	mA	
		—	—	—	—	
I _{DD_VLPR}	Very low-power run mode current at 3.0 V — all peripheral clocks disabled	—	0.63	1.32	mA	5
I _{DD_VLPR}	Very low-power run mode current at 3.0 V — all peripheral clocks enabled	—	0.78	1.46	mA	6
I _{DD_VLPW}	Very low-power wait mode current at 3.0 V	—	0.15	0.62	mA	7
I _{DD_VLPS}	Very low-power stop mode current at 3.0 V	—	19	45	μA	8
		—	145	312	μA	
		—	—	—	—	
I _{DD_LLS}	Low leakage stop mode current at 3.0 V	—	3.0	4.8	μA	8,9,10
		—	53.3	157	μA	
		—	—	—	—	
I _{DD_VLLS3}	Very low-leakage stop mode 3 current at 3.0 V	—	1.8	3.3	μA	8,9,10
		—	39.2	115	μA	
		—	—	—	—	
I _{DD_VLLS2}	Very low-leakage stop mode 2 current at 3.0 V	—	1.6	2.8	μA	8,9
		—	22.2	65	μA	
		—	—	—	—	

Table continues on the next page...

1. When the Mini-FlexBus is enabled, its clock frequency is always the same as the bus clock frequency.
2. A maximum frequency of 25 MHz for the LPTMR in VLPR mode is possible when the LPTMR is configured for pulse counting mode and is driven externally via the LPTMR_ALT1, LPTMR_ALT2, or LPTMR_ALT3 pin.

5.3.1 General Switching Specifications

These general purpose specifications apply to all signals configured for EGPIO, MTIM, CMT, PDB, IRQ, and I²C signals. The conditions are 50 pf load, V_{DD} = 1.71 V to 3.6 V, and full temperature range. The GPIO are set for high drive, no slew rate control, and no input filter, digital or analog, unless otherwise specified.

Table 9. EGPIO General Control Timing

Symbol	Description	Min.	Max.	Unit
G1	Bus clock from CLK_OUT pin high to GPIO output valid	—	32	ns
G2	Bus clock from CLK_OUT pin high to GPIO output invalid (output hold)	1	—	ns
G3	GPIO input valid to bus clock high	28	—	ns
G4	Bus clock from CLK_OUT pin high to GPIO input invalid	—	4	ns
	GPIO pin interrupt pulse width (digital glitch filter disabled) Synchronous path ¹	1.5	—	Bus clock cycles
	GPIO pin interrupt pulse width (digital glitch filter disabled, analog filter enabled) Asynchronous path ²	100	—	ns
	GPIO pin interrupt pulse width (digital glitch filter disabled, analog filter disabled) Asynchronous path ²	50	—	ns
	External reset pulse width (digital glitch filter disabled)	100	—	ns
	Mode select (MS) hold time after reset deassertion	2	—	Bus clock cycles

1. The greater synchronous and asynchronous timing must be met.
2. This is the shortest pulse that is guaranteed to be recognized.

Table 13. MCG specifications (continued)

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
J_{cyc_pll}	PLL period jitter (RMS)					8
	• $f_{vco} = 48 \text{ MHz}$	—	120	—	ps	
	• $f_{vco} = 100 \text{ MHz}$	—	50	—	ps	
J_{acc_pll}	PLL accumulated jitter over 1 μ s (RMS)					8
	• $f_{vco} = 48 \text{ MHz}$	—	1350	—	ps	
	• $f_{vco} = 100 \text{ MHz}$	—	600	—	ps	
D_{lock}	Lock entry frequency tolerance	± 1.49	—	± 2.98	%	
D_{unl}	Lock exit frequency tolerance	± 4.47	—	± 5.97	%	
t_{pll_lock}	Lock detector detection time	—	—	$150 \times 10^{-6} + 1075(1/f_{pll_ref})$	s	9

1. This parameter is measured with the internal reference (slow clock) being used as a reference to the FLL (FEI clock mode).
2. These typical values listed are with the slow internal reference clock (FEI) using factory trim and DMX32=0.
3. The resulting system clock frequencies should not exceed their maximum specified values. The DCO frequency deviation (Δf_{dco_t}) over voltage and temperature should be considered.
4. These typical values listed are with the slow internal reference clock (FEI) using factory trim and DMX32=1.
5. The resulting clock frequency must not exceed the maximum specified clock frequency of the device.
6. This specification applies to any time the FLL reference source or reference divider is changed, trim value is changed, DMX32 bit is changed, DRS bits are changed, or changing from FLL disabled (BLPE, BLPI) to FLL enabled (FEI, FEE, FBE, FBI). If a crystal/resonator is being used as the reference, this specification assumes it is already running.
7. Excludes any oscillator currents that are also consuming power while PLL is in operation.
8. This specification was obtained using a Freescale developed PCB. PLL jitter is dependent on the noise characteristics of each PCB and results will vary.
9. This specification applies to any time the PLL VCO divider or reference divider is changed, or changing from PLL disabled (BLPE, BLPI) to PLL enabled (PBE, PEE). If a crystal/resonator is being used as the reference, this specification assumes it is already running.

6.3.2 Oscillator electrical specifications

6.3.2.1 Oscillator DC electrical specifications

Table 14. Oscillator DC electrical specifications

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
V_{DD}	Supply voltage	1.71	—	3.6	V	
I_{DDOSC}	Supply current — low-power mode (HGO=0)					1
	• 32 kHz	—	500	—	nA	
	• 1 MHz	—	200	—	μ A	
	• 4 MHz	—	200	—	μ A	
	• 8 MHz (RANGE=01)	—	300	—	μ A	
		—	950	—	μ A	

Table continues on the next page...

Table 14. Oscillator DC electrical specifications (continued)

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
	16 MHz 24 MHz 32 MHz	—	1.2	—	mA	
		—	1.5	—	mA	
I _{DDOSC}	Supply current — high-gain mode (HGO=1) 32 kHz 1 MHz 4 MHz 8 MHz (RANGE=01) 16 MHz 24 MHz 32 MHz	—	25	—	μA	1
		—	300	—	μA	
		—	400	—	μA	
		—	500	—	μA	
		—	2.5	—	mA	
		—	3	—	mA	
		—	4	—	mA	
C _x	EXTAL load capacitance	—	—	—		2, 3
C _y	XTAL load capacitance	—	—	—		2, 3
R _F	Feedback resistor — low-frequency, low-power mode (HGO=0)	—	—	—	MΩ	2, 4
	Feedback resistor — low-frequency, high-gain mode (HGO=1)	—	10	—	MΩ	
	Feedback resistor — high-frequency, low-power mode (HGO=0)	—	—	—	MΩ	
	Feedback resistor — high-frequency, high-gain mode (HGO=1)	—	1	—	MΩ	
R _S	Series resistor — low-frequency, low-power mode (HGO=0)	—	—	—	kΩ	
	Series resistor — low-frequency, high-gain mode (HGO=1)	—	200	—	kΩ	
	Series resistor — high-frequency, low-power mode (HGO=0)	—	—	—	kΩ	
	Series resistor — high-frequency, high-gain mode (HGO=1) 1 MHz resonator 2 MHz resonator 4 MHz resonator 8 MHz resonator 16 MHz resonator 20 MHz resonator 32 MHz resonator	—	6.6	—	kΩ	
		—	3.3	—	kΩ	
		—	0	—	kΩ	
		—	0	—	kΩ	
		—	0	—	kΩ	
		—	0	—	kΩ	
		—	0	—	kΩ	
		—	0	—	kΩ	
V _{pp} ⁵	Peak-to-peak amplitude of oscillation (oscillator mode) — low-frequency, low-power mode (HGO=0)	—	0.6	—	V	

Table continues on the next page...

6.4 Memories and memory interfaces

6.4.1 Flash electrical specifications

This section describes the electrical characteristics of the flash memory module.

6.4.1.1 Flash timing specifications — program and erase

The following specifications represent the amount of time the internal charge pumps are active and do not include command overhead.

Table 16. NVM program/erase timing specifications

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
$t_{hvp\text{gm}4}$	Longword Program high-voltage time	—	7.5	18	μs	—
$t_{hversscr}$	Sector Erase high-voltage time	—	13	113	ms	1
$t_{hversblk32k}$	Erase Block high-voltage time for 32 KB	—	52	452	ms	1
$t_{hversblk128k}$	Erase Block high-voltage time for 128 KB	—	208	1808	ms	1

1. Maximum time based on expectations at cycling end-of-life.

6.4.1.2 Flash timing specifications — commands

Table 17. Flash command timing specifications

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
$t_{rd1blk32k}$	Read 1s Block execution time	—	—	0.5	ms	1
$t_{rd1blk128k}$	32 KB data flash 128 KB program flash	—	—	1.7	ms	
$t_{rd1sec1k}$	Read 1s Section execution time (flash sector)	—	—	60	μs	1
t_{pgmchk}	Program Check execution time	—	—	45	μs	1
t_{rdsrc}	Read Resource execution time	—	—	30	μs	1
t_{pgm4}	Program Longword execution time	—	65	145	μs	—
$t_{ersblk32k}$	Erase Flash Block execution time	—	55	465	ms	2
$t_{ersblk128k}$	32 KB data flash 128 KB program flash	—	220	1850	ms	
t_{ersscr}	Erase Flash Sector execution time	—	14	114	ms	2
$t_{pgmsec512}$	Program Section execution time	—	4.7	—	ms	—
$t_{pgmsec1k}$	512 bytes flash 1 KB flash	—	9.3	—	ms	

Table continues on the next page...

Table 17. Flash command timing specifications (continued)

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
t_{rd1all}	Read 1s All Blocks execution time	—	—	1.8	ms	1
t_{rdonce}	Read Once execution time	—	—	25	μ s	1
$t_{pgmonce}$	Program Once execution time	—	65	—	μ s	—
t_{ersall}	Erase All Blocks execution time	—	275	2350	ms	2
t_{vfykey}	Verify Backdoor Access Key execution time	—	—	30	μ s	1
$t_{pgmpart32k}$	Program Partition for EEPROM execution time • 32 KB FlexNVM	—	70	—	ms	—
$t_{setramff}$	Set FlexRAM Function execution time: • Control Code 0xFF	—	50	—	μ s	—
$t_{setram8k}$	• 8 KB EEPROM backup	—	0.3	0.5	ms	—
$t_{setram32k}$	• 32 KB EEPROM backup	—	0.7	1.0	ms	—
Byte-write to FlexRAM for EEPROM operation						
$t_{eewr8bers}$	Byte-write to erased FlexRAM location execution time	—	175	260	μ s	3
$t_{eewr8b8k}$	Byte-write to FlexRAM execution time: • 8 KB EEPROM backup	—	340	1700	μ s	—
$t_{eewr8b16k}$	• 16 KB EEPROM backup	—	385	1800	μ s	—
$t_{eewr8b32k}$	• 32 KB EEPROM backup	—	475	2000	μ s	—
Word-write to FlexRAM for EEPROM operation						
$t_{eewr16bers}$	Word-write to erased FlexRAM location execution time	—	175	260	μ s	—
$t_{eewr16b8k}$	Word-write to FlexRAM execution time: • 8 KB EEPROM backup	—	340	1700	μ s	—
$t_{eewr16b16k}$	• 16 KB EEPROM backup	—	385	1800	μ s	—
$t_{eewr16b32k}$	• 32 KB EEPROM backup	—	475	2000	μ s	—
Longword-write to FlexRAM for EEPROM operation						
$t_{eewr32bers}$	Longword-write to erased FlexRAM location execution time	—	360	540	μ s	—
$t_{eewr32b8k}$	Longword-write to FlexRAM execution time: • 8 KB EEPROM backup	—	545	1950	μ s	—
$t_{eewr32b16k}$	• 16 KB EEPROM backup	—	630	2050	μ s	—
$t_{eewr32b32k}$	• 32 KB EEPROM backup	—	810	2250	μ s	—

1. Assumes 25 MHz flash clock frequency.
2. Maximum times for erase parameters based on expectations at cycling end-of-life.
3. For byte-writes to an erased FlexRAM location, the aligned word containing the byte must be erased.

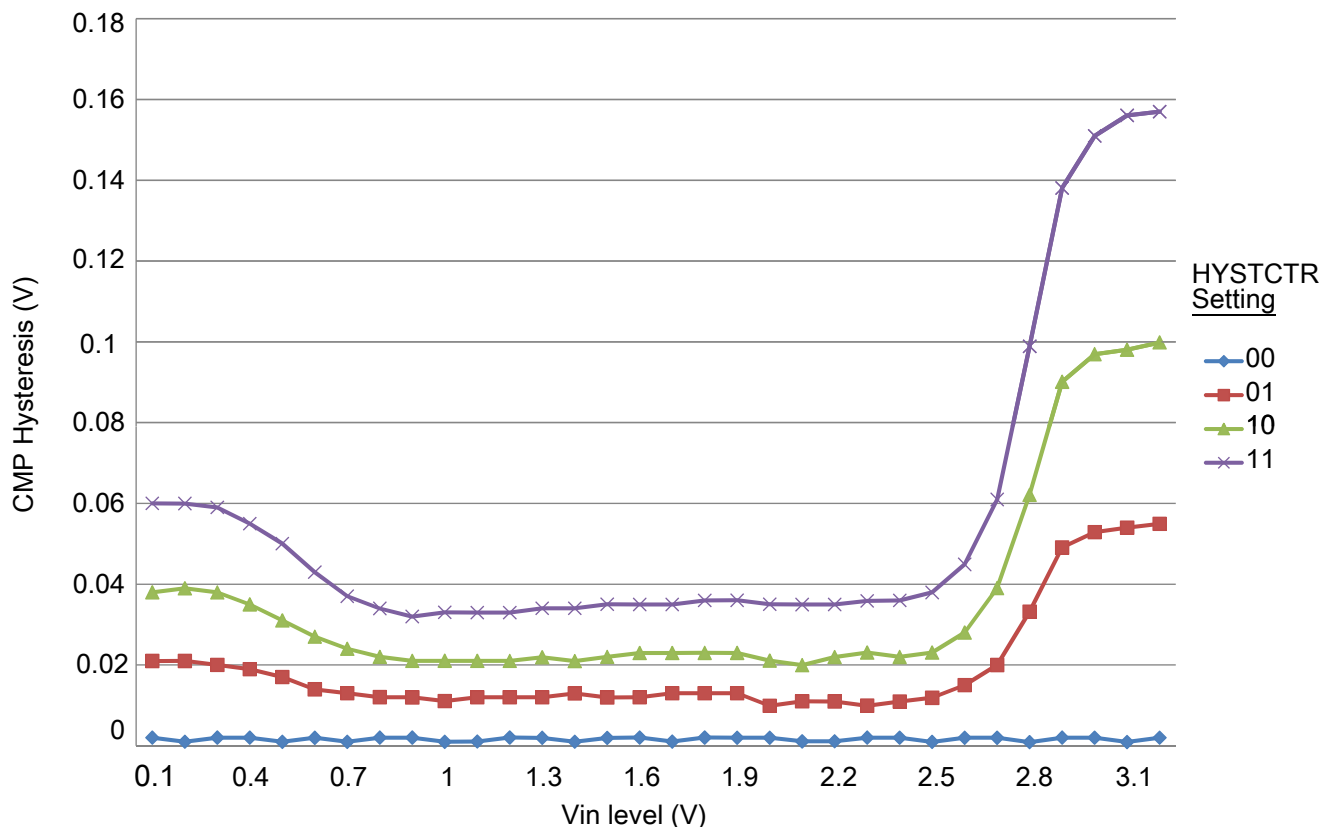


Figure 11. Typical hysteresis vs. Vin level (VDD = 3.3 V, PMODE = 1)

6.6.3 12-bit DAC electrical characteristics

6.6.3.1 12-bit DAC operating requirements

Table 25. 12-bit DAC operating requirements

Symbol	Description	Min.	Max.	Unit	Notes
V_{DDA}	Supply voltage	1.71	3.6	V	
V_{DACR}	Reference voltage	1.13	3.6	V	1
C_L	Output load capacitance	—	100	pF	2
I_L	Output load current	—	1	mA	

1. The DAC reference can be selected to be V_{DDA} or V_{REFH} .
2. A small load capacitance (47 pF) can improve the bandwidth performance of the DAC.

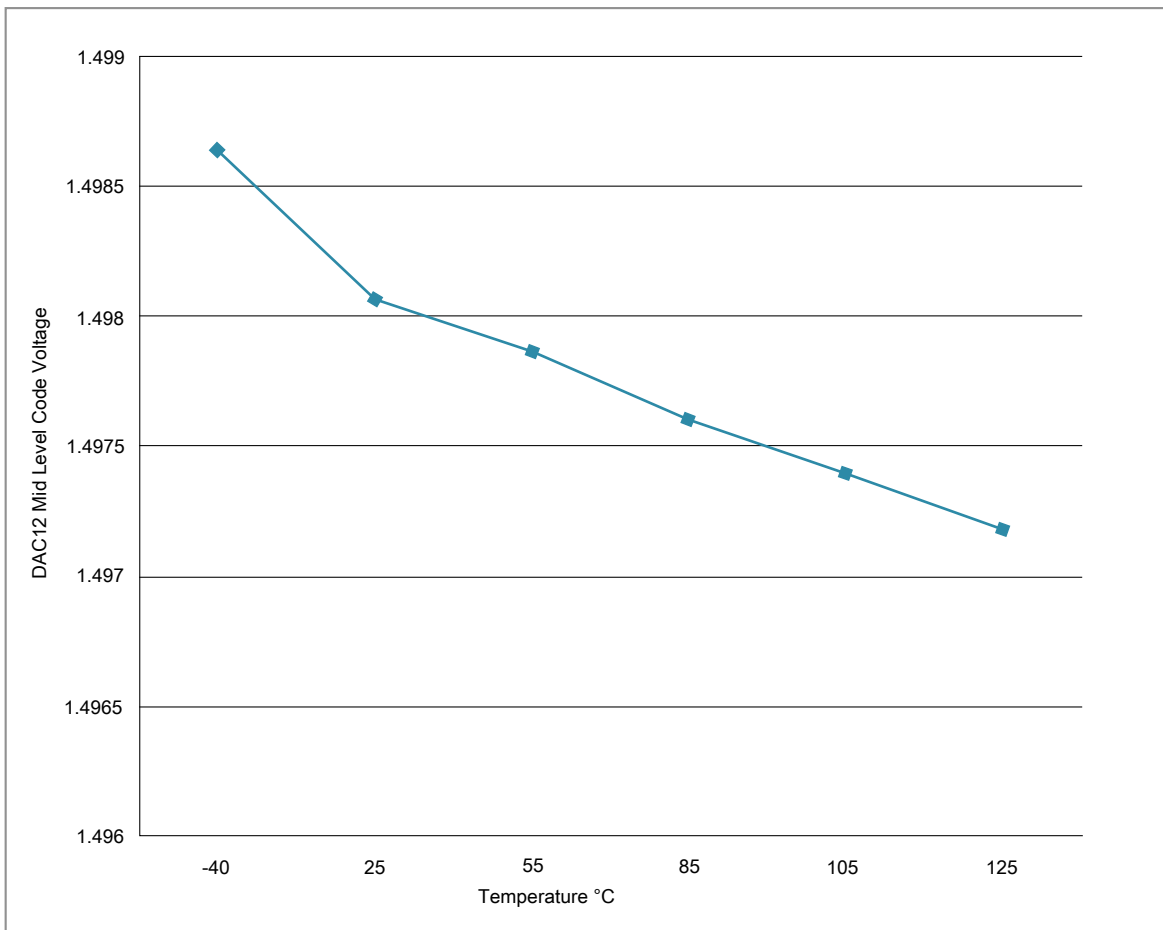


Figure 13. Offset at half scale vs. temperature

6.6.4 Voltage reference electrical specifications

Table 27. VREF full-range operating requirements

Symbol	Description	Min.	Max.	Unit	Notes
V_{DDA}	Supply voltage	1.71	3.6	V	—
C_L	Output load capacitance	100		nF	1

- C_L must be connected to VREF_OUT if the VREF_OUT functionality is being used for either an internal or external reference.

Table 28. VREF full-range operating behaviors

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
V_{out}	Voltage reference output with factory trim at nominal V_{DDA} and temperature=25°C	1.1965	1.2	1.2027	V	
V_{out}	Voltage reference output — factory trim	1.144	—	1.266	V	

Table continues on the next page...

NOTE

6.8.2 USB DCD electrical specifications

Table 31. USB0 DCD electrical specifications

Symbol	Description	Min.	Typ.	Max.	Unit
V _{DP_SRC}	USB_DP source voltage (up to 250 μ A)	0.5	—	0.7	V
V _{LGC}	Threshold voltage for logic high	0.8	—	2.0	V
I _{DP_SRC}	USB_DP source current	7	10	13	μ A
I _{DM_SINK}	USB_DM sink current	50	100	150	μ A
R _{DM_DWN}	D- pulldown resistance for data pin contact detect	14.25	—	24.8	k Ω
V _{DAT_REF}	Data detect voltage	0.25	0.33	0.4	V

6.8.3 USB VREG electrical specifications

Table 32. USB VREG electrical specifications

Symbol	Description	Min.	Typ. ¹	Max.	Unit	Notes
V _{REGIN}	Input supply voltage	2.7	—	5.5	V	
I _{DDon}	Quiescent current — Run mode, load current equal zero, input supply (V _{REGIN}) > 3.6 V	—	120	186	μ A	
I _{DDstby}	Quiescent current — Standby mode, load current equal zero	—	1.1	10	μ A	
I _{DDoff}	Quiescent current — Shutdown mode - V_{REGIN} = 5.0 V and temperature=25 $^{\circ}$C - Across operating voltage and temperature	—	650	—	nA	
		—	—	4	μ A	
I _{LOADrun}	Maximum load current — Run mode	—	—	120	mA	
I _{LOADstby}	Maximum load current — Standby mode	—	—	1	mA	
V _{Reg33out}	Regulator output voltage — Input supply (V _{REGIN}) > 3.6 V - Run mode - Standby mode	3	3.3	3.6	V	
		2.1	2.8	3.6	V	
V _{Reg33out}	Regulator output voltage — Input supply (V _{REGIN}) < 3.6 V, pass-through mode	2.1	—	3.6	V	2
C _{OUT}	External output capacitor	1.76	2.2	8.16	μ F	
ESR	External output capacitor equivalent series resistance	1	—	100	m Ω	
I _{LIM}	Short circuit current	—	290	—	mA	

1. Typical values assume V_{REGIN} = 5.0 V, Temp = 25 $^{\circ}$ C unless otherwise stated.

2. Operating in pass-through mode: regulator output voltage equal to the input voltage minus a drop proportional to I_{Load}.

Table 34. SPI slave mode timing (continued)

Num.	Symbol	Description	Min.	Max.	Unit	Comment
3	t_{Lead}	Enable lead time	1	—	t_{BUS}	—
4	t_{Lag}	Enable lag time	1	—	t_{BUS}	—
5	t_{WSPSCK}	Clock (SPSCK) high or low time	$t_{BUS} - 30$	—	ns	—
6	t_{SU}	Data setup time (inputs)	19.5	—	ns	—
7	t_{HI}	Data hold time (inputs)	0	—	ns	—
8	t_a	Slave access time	—	t_{BUS}	ns	Time to data active from high-impedance state
9	t_{dis}	Slave MISO disable time	—	t_{BUS}	ns	Hold time to high-impedance state
10	t_v	Data valid (after SPSCK edge)	—	27	ns	—
11	t_{HO}	Data hold time (outputs)	0	—	ns	—
12	t_{RI}	Rise time input	—	$t_{BUS} - 25$	ns	—
	t_{FI}	Fall time input				
13	t_{RO}	Rise time output	—	25	ns	—
	t_{FO}	Fall time output				

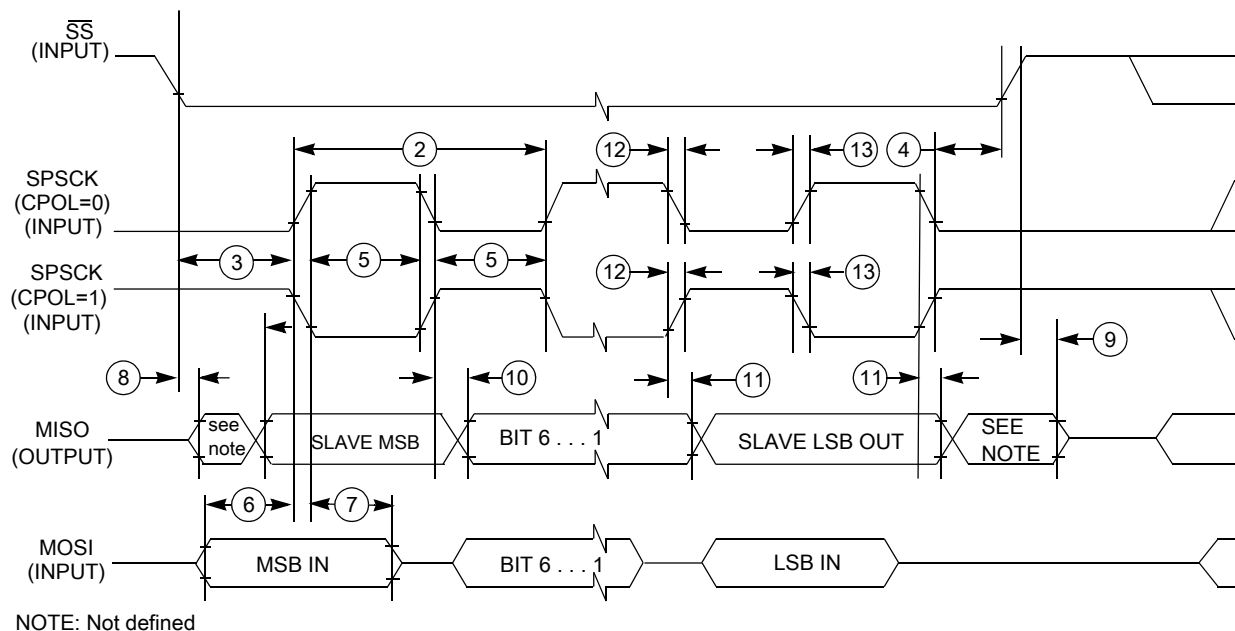


Figure 16. SPI slave mode timing (CPHA=0)

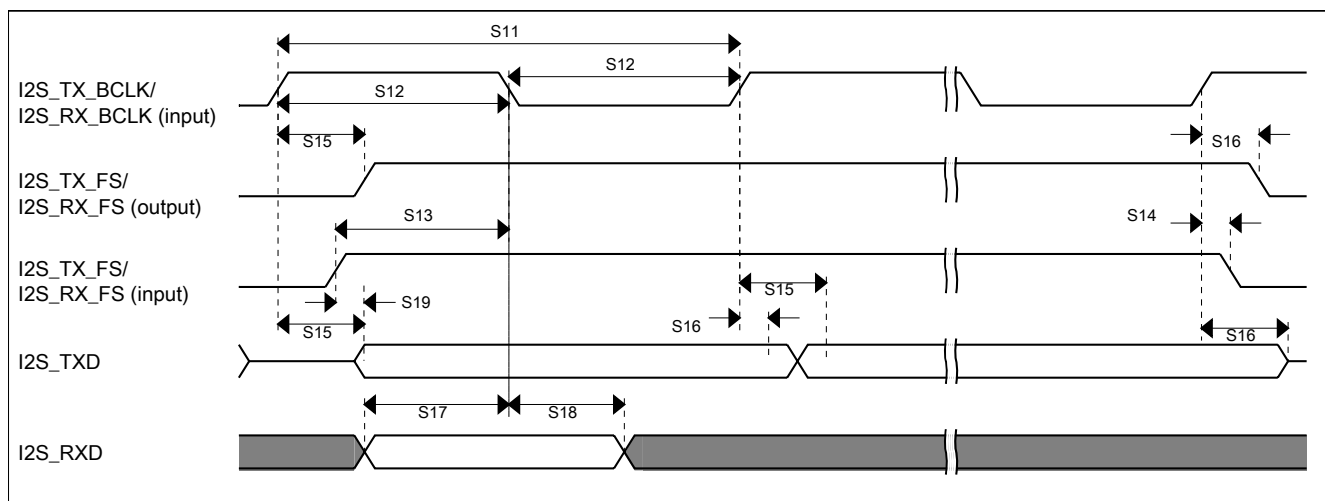


Figure 19. I2S/SAI timing — slave modes

6.9 Human-machine interfaces (HMI)

6.9.1 TSI electrical specifications

Table 37. TSI electrical specifications

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
V_{DDTSI}	Operating voltage	1.71	—	3.6	V	
C_{ELE}	Target electrode capacitance range	1	20	500	pF	1
f_{REFmax}	Reference oscillator frequency	—	5.5	14	MHz	2
f_{ELEmax}	Electrode oscillator frequency	—	0.5	4.0	MHz	3
C_{REF}	Internal reference capacitor	0.5	1	1.2	pF	
V_{DELTA}	Oscillator delta voltage	100	600	760	mV	4
I_{REF}	Reference oscillator current source base current 1uA setting (REFCHRG=0) 32uA setting (REFCHRG=31)	— —	1.133 36	1.5 50	μ A	3, 5
I_{ELE}	Electrode oscillator current source base current 1uA setting (EXTCHRG=0) 32uA setting (EXTCHRG=31)	— —	1.133 36	1.5 50	μ A	3, 6
Pres5	Electrode capacitance measurement precision	—	8.3333	38400	fF/count	7
Pres20	Electrode capacitance measurement precision	—	8.3333	38400	fF/count	8
Pres100	Electrode capacitance measurement precision	—	8.3333	38400	fF/count	9
MaxSens	Maximum sensitivity	0.003	12.5	—	fF/count	10
Res	Resolution	—	—	16	bits	
T_{Con20}	Response time @ 20 pF	8	15	25	μ s	11
I_{TSI_RUN}	Current added in run mode	—	55	—	μ A	
I_{TSI_LP}	Low power mode current adder	—	1.3	2.5	μ A	12

Pinout

64-pin	48-pin	44-pin	32-pin	Default	ALT0	ALT1	ALT2	ALT3	ALT4	ALT5	ALT6	ALT7	EzPort
22	18	16	13	USB0_DP	USB0_DP								
23	19	17	14	VSS	VSS								
24	20	18	—	VDD	VDD								
25	21	19	15	ADC0_SE8/ TSI0_CH0	ADC0_SE8/ TSI0_CH0	PTA6		LPTMR_ ALT1	FTM_FLT1	FBa_D7	FBa_AD17		
26	—	—	—	ADC0_SE9/ TSI0_CH1	ADC0_SE9/ TSI0_CH1	PTD2	FTM0_QD_ PHA	RGPIO10	FTM0_CH0				
27	22	20	—	ADC0_SE10/ TSI0_CH2	ADC0_SE10/ TSI0_CH2	PTD3	FTM0_QD_ PHB	RGPIO11	FTM0_CH1	FBa_D6	FBa_AD0		
28	—	—	—	ADC0_SE11/ TSI0_CH3	ADC0_SE11/ TSI0_CH3	PTD4		RGPIO12			FBa_D7		
29	—	—	—	ADC0_SE12/ TSI0_CH4	ADC0_SE12/ TSI0_CH4	PTD5		RGPIO13			FBa_D6		
30	23	21	16	ADC0_SE13/ TSI0_CH5	ADC0_SE13/ TSI0_CH5	PTA7	UART0_TX		FTM0_QD_ PHA		FBa_D5		
31	24	22	—	ADC0_SE14/ TSI0_CH6	ADC0_SE14/ TSI0_CH6	PTD6	UART0_RX	RGPIO14			FBa_D4		
32	—	—	—	ADC0_SE15/ TSI0_CH7	ADC0_SE15/ TSI0_CH7	PTD7	UART0_ CTS_b	I2C3_SCL	RGPIO15		FBa_D3		
33	—	—	—	TSI0_CH8	TSI0_CH8	PTE0	UART0_ RTS_b	I2C3_SDA			FBa_D2		
34	—	—	—	TSI0_CH9	TSI0_CH9	PTE1	SPI0_SS		FTM_FLT0		FBa_D1		
35	25	23	17	IRQ/ EZP_MS_b	Disabled	PTB0		I2C0_SCL		IRQ/ EZP_MS_b			EZP_CS_b
36	26	24	18	TSI0_CH10	TSI0_CH10	PTB1	SPI0_SCLK	I2C0_SDA	FTM_FLT2	LPTMR_ ALT2	FTM0_QD_ PHB	FB_CLKOUT	
37	—	—	—	TSI0_CH11	TSI0_CH11	PTE2		I2C3_SCL			FBa_D0		
38	—	—	—	ADC0_SE16/ TSI0_CH12	ADC0_SE16/ TSI0_CH12	PTE3	SPI0_MOSI	I2C3_SDA			FBa_OE_b		
39	27	25	19	ADC0_SE17/ TSI0_CH13	ADC0_SE17/ TSI0_CH13	PTB2	SPI0_MISO				FBa_CS0_b		
40	28	26	20	ADC0_SE18/ TSI0_CH14	ADC0_SE18/ TSI0_CH14	PTB3	SPI0_MOSI			FBa_CS1_b	FBa_ALE		
41	29	—	—	ADC0_SE19/ TSI0_CH15	ADC0_SE19/ TSI0_CH15	PTE4	UART0_ RTS_b	LPTMR_ ALT3	SPI1_SS		FBa_AD1		
42	30	—	—	ADC0_SE20	ADC0_SE20	PTE5	UART0_ CTS_b	I2C1_SCL	SPI1_SCLK		FBa_AD2		
43	—	—	—	ADC0_SE21	ADC0_SE21	PTE6	UART0_RX	I2C1_SDA	SPI1_MISO		FBa_AD3		
44	31	27	—	ADC0_SE22	ADC0_SE22	PTE7	UART0_TX	PDB0_ EXTRG	SPI1_MOSI	FBa_RW_b	FBa_AD4		
45	32	28	21	BKGD/ MS	Disabled	PTB4	BKGD/ MS						
46	33	29	22	XTAL2	XTAL2	PTB5							
47	34	30	23	EXTAL2	EXTAL2	PTB6							
48	35	31	24	VDD	VDD								
49	36	32	25	VSS	VSS								

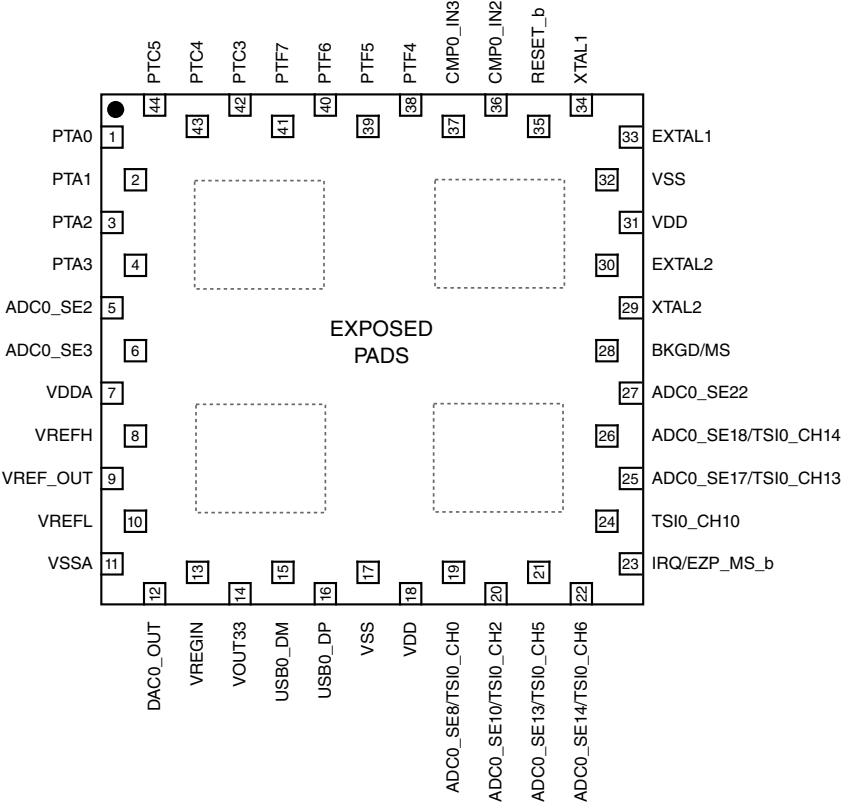


Figure 22. 44-pin Laminate QFN

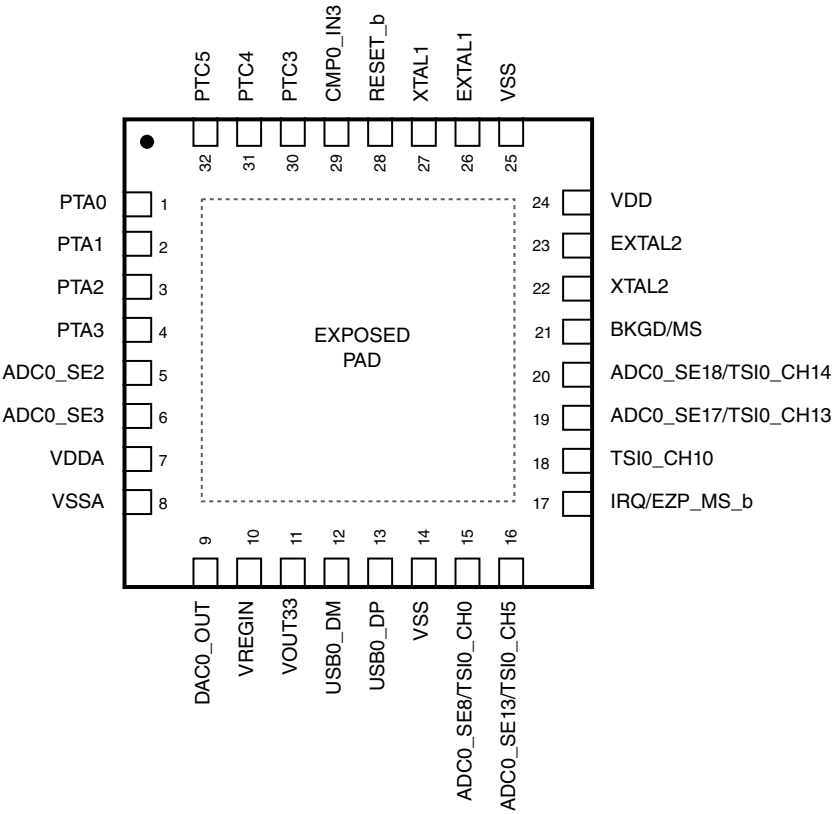


Figure 23. 32-pin QFN

8.3 Module-by-module signals

NOTE

- On PTB0, EZP_MS_b is active only during reset. Refer to the detailed boot description.
- PTC1 is open drain.

Table 38. Module signals by GPIO port and pin

64-pin	48-pin	44-pin	32-pin	Port	Module signal(s)
Power and ground					
1					VDD
24	20	18			VDD

Table continues on the next page...

Table 38. Module signals by GPIO port and pin (continued)

64-pin	48-pin	44-pin	32-pin	Port	Module signal(s)
48	35	31	24		VDD
2					VSS
23	19	17	14		VSS
49	36	32	25		VSS
System					
45	32	28	21	PTB4	BKGD/MS
12	8	6	6	PTA5	CLKOUT
62	46	42	30	PTC3	CLKOUT
10	6	4	4	PTA3	EZP_CLK
11	7	5	5	PTA4	EZP_DI
12	8	6	6	PTA5	EZP_DO
35	25	23	17	PTB0	IRQ/EZP_MS_b, EZP_CS_b
52	39	35	28	PTC1	RESET_b
OSC					
50	37	33	26	PTB7	EXTAL1
47	34	30	23	PTB6	EXTAL2
51	38	34	27	PTC0	XTAL1
46	33	29	22	PTB5	XTAL2
LLWU					
4				PTC7	LLWU_P0
6	2			PTD1	LLWU_P1
12	8	6	6	PTA5	LLWU_P2
30	23	21	16	PTA7	LLWU_P3
32				PTD7	LLWU_P4
35	25	23	17	PTB0	LLWU_P5
36	26	24	18	PTB1	LLWU_P6
39	27	25	19	PTB2	LLWU_P7
44	31	27		PTE7	LLWU_P8
45	32	28	21	PTB4	LLWU_P9
55				PTF2	LLWU_P10
56	40	36		PTF3	LLWU_P11
57	41	37	29	PTC2	LLWU_P12
59	43	39		PTF5	LLWU_P13
62	46	42	30	PTC3	LLWU_P14
63	47	43	31	PTC4	LLWU_P15
RGPIO					
51	38	34	27	PTC0	RGPIO0
56	40	36		PTF3	RGPIO1
57	41	37	29	PTC2	RGPIO2

Table continues on the next page...

Table 38. Module signals by GPIO port and pin (continued)

64-pin	48-pin	44-pin	32-pin	Port	Module signal(s)
62	46	42	30	PTC3	RGPIO3
63	47	43	31	PTC4	RGPIO4
64	48	44	32	PTC5	RGPIO5
3				PTC6	RGPIO6
4				PTC7	RGPIO7
5	1			PTD0	RGPIO8
6	2			PTD1	RGPIO9
26				PTD2	RGPIO10
27	22	20		PTD3	RGPIO11
28				PTD4	RGPIO12
29				PTD5	RGPIO13
31	24	22		PTD6	RGPIO14
32				PTD7	RGPIO15
LPTMR					
25	21	19	15	PTA6	LPTMR_ALT1
36	26	24	18	PTB1	LPTMR_ALT2
41	29			PTE4	LPTMR_ALT3
LPTMR-TOD					
50	37	33	26	PTB7	EXTAL1
47	34	30	23	PTB6	EXTAL2
25	21	19	15	PTA6	LPTMR_ALT1
36	26	24	18	PTB1	LPTMR_ALT2
41	29			PTE4	LPTMR_ALT3
51	38	34	27	PTC0	XTAL1
46	33	29	22	PTB5	XTAL2
PTA					
7	3	1	1	PTA0	PTA0
8	4	2	2	PTA1	PTA1
9	5	3	3	PTA2	PTA2
10	6	4	4	PTA3	PTA3
11	7	5	5	PTA4	PTA4
12	8	6	6	PTA5	PTA5
25	21	19	15	PTA6	PTA6
30	23	21	16	PTA7	PTA7
PTB					
35	25	23	17	PTB0	PTB0
36	26	24	18	PTB1	PTB1
39	27	25	19	PTB2	PTB2
40	28	26	20	PTB3	PTB3

Table continues on the next page...

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